Notice of References Cited Application/Control No. 10/661,503 Examiner Phillip C. Lee Applicant(s)/Patent Under Reexamination HIKAWA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,069,536	06-2006	Yaung, Alan Tsu-I	717/102
*	В	US-2003/0061266	03-2003	Ouchi, Norman Ken	709/106
*	C	US-5,918,226	06-1999	Tarumi et al.	707/10
*	D	US-7,200,860	04-2007	Ghaffar, Junaid	726/2
*	E	US-2006/0005229	01-2006	Palekar et al.	726/001
*	F	US-7,168,077	01-2007	Kim et al.	718/106
*	G	US-6,772,216	08-2004	Ankireddipally et al.	709/230
*	Н	US-2002/0055849	05-2002	Georgakopoulos et al.	705/1
*	ı	US-5,596,750	01-1997	Li et al.	718/101
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.